EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	0	testing IC signal quality	USPAT	ADJ	OFF	2006/02/18 20:24
L2	0	IC signal quality	USPAT	ADJ	OFF	2006/02/18 20:24
L3	1	integrated circuit signal quality	USPAT	ADJ	OFF	2006/02/18 20:28
L4	13	"614040"	USPAT	OR	OFF	2006/02/18 20:34
L5	0	("signaltestingofintegratedcircuitchips").PN.	USPAT; USOCR	OR	OFF	2006/02/18 20:35
L6	0	signal testing of integrated circuit chips	USPAT	WITH	OFF	2006/02/18 20:36
L7	1187	power and ground bounce	USPAT	WITH	OFF	2006/02/18 21:06
L8	1	"614040"	US-PGPUB	OR	OFF	2006/02/18 21:06

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Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	0	testing IC signal quality	USPAT	ADJ	OFF	2006/02/18 20:24
L2	0	IC signal quality	USPAT	ADJ	OFF	2006/02/18 20:24
L3	1	integrated circuit signal quality	USPAT	ADJ	OFF	2006/02/18 20:28
L4	13	"614040"	USPAT	OR	OFF	2006/02/18 20:34
L5	0	("signaltestingofintegratedcircuitchips").PN.	USPAT; USOCR	OR	OFF	2006/02/18 20:35
L6	0	signal testing of integrated circuit chips	USPAT	WITH	OFF	2006/02/18 20:36
L7	1187	power and ground bounce	USPAT	WITH	OFF	2006/02/18 21:27
L8	1	"614040"	US-PGPUB	OR	OFF	2006/02/18 21:26
L9	54	(power and ground bounce).ab.	USPAT	WITH	OFF	2006/02/18 21:27
L10	29089	(power and ground bounce).clm.	USPAT	OR	ON	2006/02/18 21:28
L11	14962	(power with ground bounce).clm.	USPAT	OR	ON	2006/02/18 21:28
L12	27	l9 and l11	USPAT	OR	OFF	2006/02/18 21:28